IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re th	he Application of:	
WALTHERUS W. VAN DEN HOOGENHOF		Art Group:
Application No.:		Examiner:
Filed:		
For:	SAMPLE CONTAINER, MEASURING DEVICE AND METHOD FOR X-RAY ANALYSIS OF LIQUIDS	
-	missioner for Patents Box 1450	
Alexandria, VA 22313-1450		
REQUEST FOR PRIORITY		
Sir:		
Applicant respectfully requests a convention priority for the above-captioned		
application, namely:		
	APPLIC COUNTRY NUM	CATION IBER DATE OF FILING
		9937.9 13 March 2001
☐ A certified copy of the document is being submitted herewith.		
	Respectfully submitted,	
	В	Blakely, Sokoloff, Taylor & Zafman LLP
Los Ai		ric S. Hyman, Reg. No. 30,139